



Power MOSFETS

DATASHEET

LM60A05NAO2A

N-Channel
Enhancement Mode MOSFET

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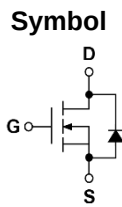
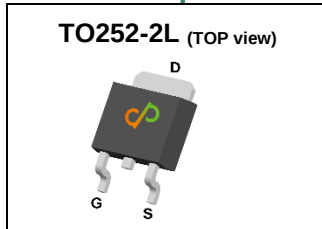


Quality Management Systems

ISO 9001:2015 Certificate

N-Channel Enhancement Mode MOSFET

Pin Description



Product Summary

Symbol	N-Channel	Unit
V_{DSS}	60	V
$R_{DS(ON)-Max}$	105	m Ω
I_D	9.8	A

Feature

- Fast switching speed
- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- 100% UIS Tested

Applications

- DC/DC Converters

Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM60A05NAO2A	TO252-2L	Tape & Reel	3000 / Tape & Reel	60A05 □□□□□□

Note : □□□□□□ = Lot Code

Absolute Maximum Ratings (T_J=25°C Unless Otherwise Noted)

Symbol	Parameter	N-Channel	Unit
V_{DSS}	Drain-Source Voltage	60	V
V_{GSS}	Gate-Source Voltage	±20	
T_J	Maximum Junction Temperature	150	°C
T_{STG}	Storage Temperature Range	-55 to 150	°C
$I_{DM}^{①}$	Pulse Drain Current Tested	$T_c=25^{\circ}C$ 16	A
I_D	Continuous Drain Current	$T_c=25^{\circ}C$ 9.8	A
		$T_c=100^{\circ}C$ 6.2	
P_D	Maximum Power Dissipation	$T_c=25^{\circ}C$ 20.8	W
		$T_c=100^{\circ}C$ 8.3	
$I_{AS}^{②}$	Avalanche Current, Single pulse	L=0.1mH 8.5	A
$E_{AS}^{②}$	Avalanche Energy, Single pulse	L=0.1mH 3.6	mJ

Thermal Characteristics

Symbol	Parameter	Rating	Unit
$R_{\theta JC}$	Thermal Resistance-Junction to Case	Steady State 6	°C/W
$R_{\theta JA}^{③}$	Thermal Resistance-Junction to Ambient	Steady State 65	°C/W

Note ① : Max. current is limited by junction temperature.

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150°C

Note ③ : Surface Mounted on 1in² FR-4 board with 1oz

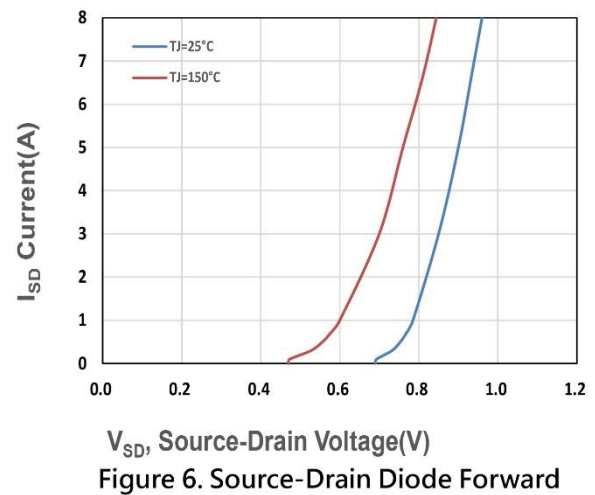
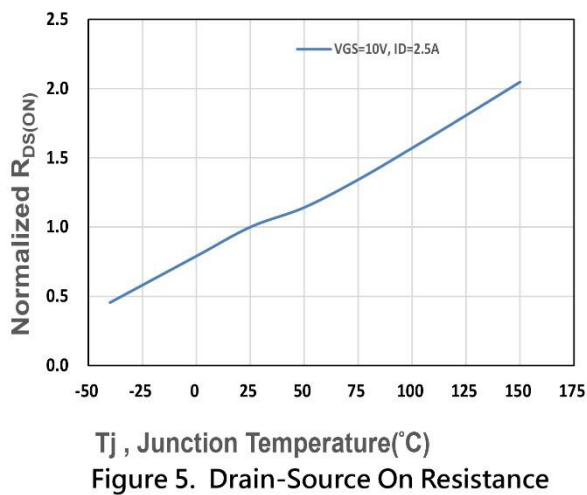
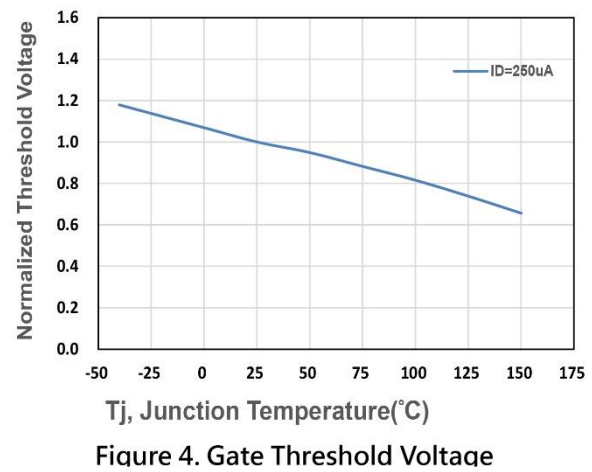
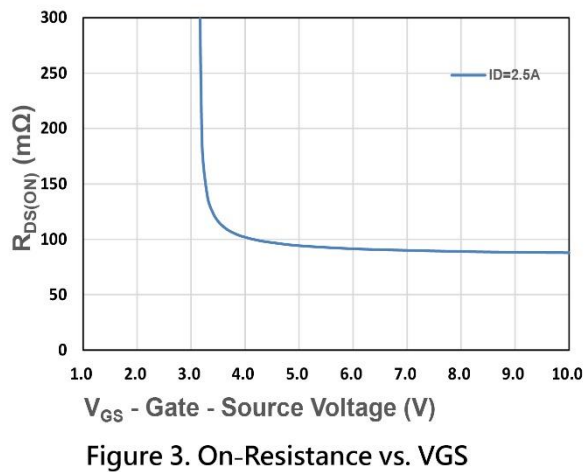
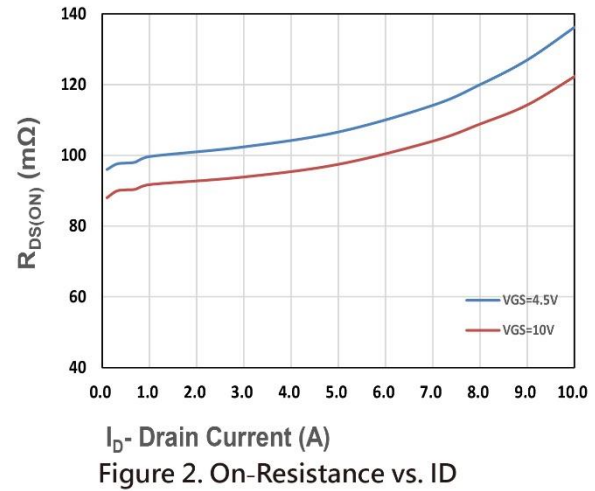
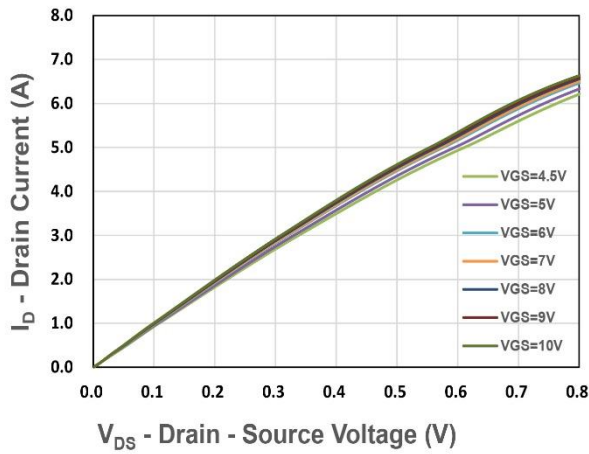
N-Channel Electrical Characteristics ($T_J=25^{\circ}\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Electrical Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =250uA	60	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =48V, V _{GS} =0V	-	-	1	uA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250uA	1	2	3	V
I _{GSS}	Gate Leakage Current	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
R _{DS(ON)} ^④	Drain-Source On-state Resistance	V _{GS} =10V, I _{DS} =2.5A	-	88	105	mΩ
		V _{GS} =4.5V, I _{DS} =2A	-	96	125	
gfs	Forward Transconductance	V _{DS} =3V, I _{DS} =1.25A	-	5.4	-	S
Dynamic Characteristics [®]						
R _G	Gate Resistance	V _{GS} =0V, V _{DS} =0V, Freq.=1MHz	-	3.4	-	Ω
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =30V, Freq.=1MHz	-	352	-	pF
C _{oss}	Output Capacitance		-	17.3	-	
C _{rss}	Reverse Transfer Capacitance		-	13	-	
td(ON)	Turn-on Delay Time	V _{GS} =10V, V _{DS} =30V, I _D =1A, R _{GEN} =6Ω	-	4.3	-	nS
t _r	Turn-on Rise Time		-	16.9	-	
t _{d(OFF)}	Turn-off Delay Time		-	12.5	-	
t _f	Turn-off Fall Time		-	23.4	-	
Q _g	Total Gate Charge	V _{GS} =4.5V, V _{DS} =30V I _D =2.5A	-	4	-	nC
Q _g	Total Gate Charge	V _{GS} =10V, V _{DS} =30V, I _D =2.5A	-	8.5	-	
Q _{gs}	Gate-Source Charge		-	1.92	-	
Q _{gd}	Gate-Drain Charge		-	1.83	-	
Source-Drain Characteristics						
V _{SD} ^④	Diode Forward Voltage	I _{SD} =1.25A, V _{GS} =0V	-	0.8	1.1	V
t _{rr}	Reverse Recovery Time	I _F =1.25A, V _R =30V	-	14.5	-	nS
Q _{rr}	Reverse Recovery Charge	dI _F /dt=100A/μs	-	9.3	-	nC

Note ④ : Pulse test (pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$).

Note ⑤ : Guaranteed by design, not subject to production testing.

N-Channel Typical Characteristics



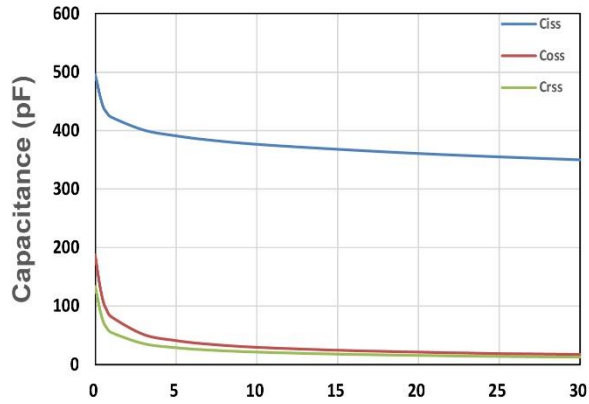


Figure 7. Capacitance

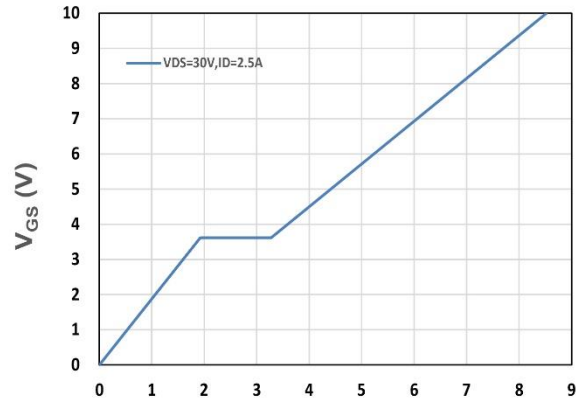


Figure 8. Gate Charge Characteristics

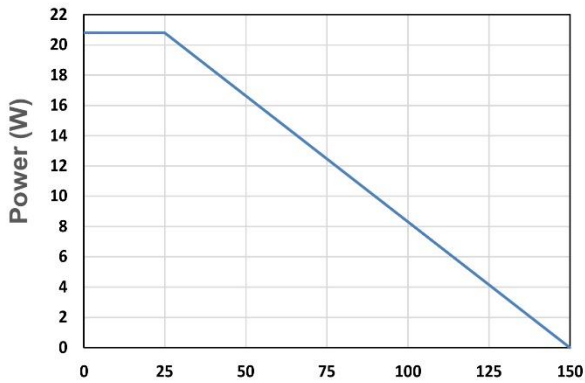


Figure 9. Power Dissipation

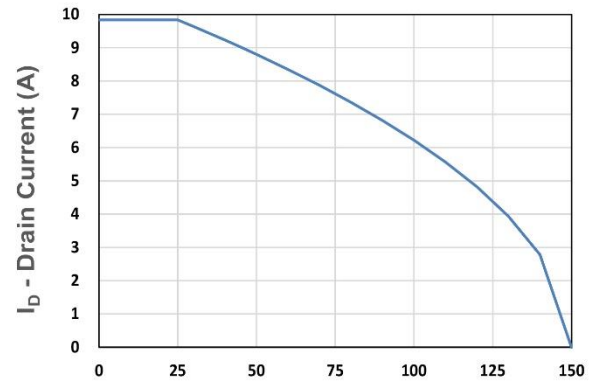


Figure 10. Drain Current

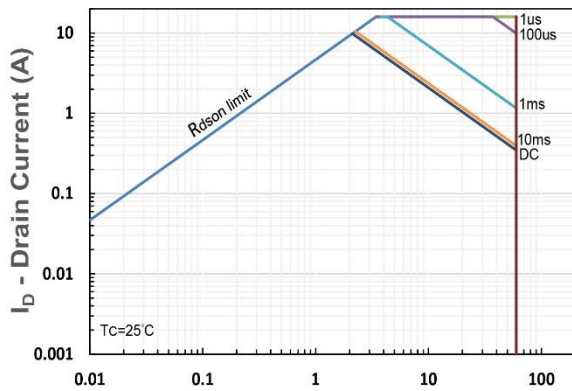


Figure 11. Safe Operating Area

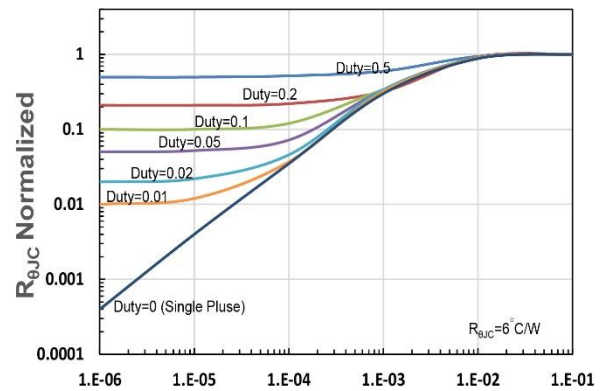


Figure 12. $R_{\theta JC}$ Transient Thermal Impedance